



**ALPHA & OMEGA**  
SEMICONDUCTOR

**AOT2916L/AOTF2916L**  
**100V N-Channel MOSFET**

### General Description

The AOT2916L & AOTF2916L uses trench MOSFET technology that is uniquely optimized to provide the most efficient high frequency switching performance. Both conduction and switching power losses are minimized due to an extremely low combination of  $R_{DS(ON)}$ , Ciss and Coss. This device is ideal for boost converters and synchronous rectifiers for consumer, telecom, industrial power supplies and LED backlighting.

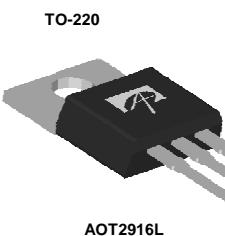
### Product Summary

$V_{DS}$	100V
$I_D$ (at $V_{GS}=10V$ )	23A / 17A
$R_{DS(ON)}$ (at $V_{GS}=10V$ )	< 34mΩ
$R_{DS(ON)}$ (at $V_{GS}=4.5V$ )	< 43.5mΩ

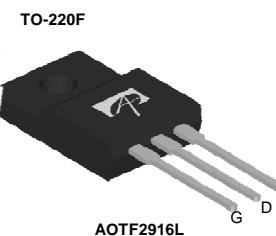
100% UIS Tested  
100%  $R_g$  Tested



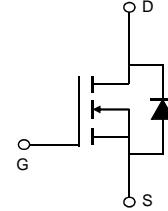
Top View



TO-220



TO-220F



AOT2916L

AOTF2916L

**Absolute Maximum Ratings  $T_A=25^\circ\text{C}$  unless otherwise noted**

Parameter	Symbol	AOT2916L	AOTF2916L	Units
Drain-Source Voltage	$V_{DS}$	100		V
Gate-Source Voltage	$V_{GS}$		$\pm 20$	V
Continuous Drain Current	$I_C=25^\circ\text{C}$	$I_D$	23	A
Current			16	
Pulsed Drain Current <sup>C</sup>	$I_{DM}$		50	
Continuous Drain Current	$T_C=25^\circ\text{C}$	$I_{DSM}$	5	A
Current			4	
Avalanche Current <sup>C</sup>	$I_{AS}$		8	A
Avalanche energy L=0.1mH <sup>C</sup>	$E_{AS}$		3	mJ
Power Dissipation <sup>B</sup>	$T_C=25^\circ\text{C}$	$P_D$	41.5	W
			20.5	
Power Dissipation <sup>A</sup>	$T_A=25^\circ\text{C}$	$P_{DSM}$	2.1	W
			1.3	
Junction and Storage Temperature Range	$T_J, T_{STG}$		-55 to 175	°C

### Thermal Characteristics

Parameter	Symbol	AOT2916L	AOTF2916L	Units
Maximum Junction-to-Ambient <sup>A</sup> $t \leq 10\text{s}$	$R_{\theta JA}$	15	15	°C/W
Maximum Junction-to-Ambient <sup>A D</sup> Steady-State		60	60	°C/W
Maximum Junction-to-Case	$R_{\theta JC}$	3.6	6.4	°C/W

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	100			V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=100\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			1 5	$\mu\text{A}$
$I_{\text{GSS}}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 20\text{V}$			$\pm 100$	nA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1.6	2	2.7	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=10\text{V}, V_{DS}=5\text{V}$	50			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=10\text{A}$ $T_J=125^\circ\text{C}$		28 51	34 62	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=3\text{A}$		35	43.5	$\text{m}\Omega$
$g_{\text{FS}}$	Forward Transconductance	$V_{DS}=5\text{V}, I_D=10\text{A}$		28		S
$V_{\text{SD}}$	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.75	1	V
$I_S$	Maximum Body-Diode Continuous Current				23	A
<b>DYNAMIC PARAMETERS</b>						
$C_{\text{iss}}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=50\text{V}, f=1\text{MHz}$		870		pF
$C_{\text{oss}}$	Output Capacitance			68		pF
$C_{\text{rss}}$	Reverse Transfer Capacitance			3.5		pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		7		$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=50\text{V}, I_D=10\text{A}$		12.5	20	nC
$Q_g(4.5\text{V})$	Total Gate Charge			5.5	10	nC
$Q_{\text{gs}}$	Gate Source Charge			2.5		nC
$Q_{\text{gd}}$	Gate Drain Charge			2		nC
$t_{\text{D(on)}}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=50\text{V}, R_L=5\Omega, R_{\text{GEN}}=3\Omega$		7.5		ns
$t_r$	Turn-On Rise Time			3.5		ns
$t_{\text{D(off)}}$	Turn-Off Delay Time			23		ns
$t_f$	Turn-Off Fall Time			5.5		ns
$t_{\text{rr}}$	Body Diode Reverse Recovery Time	$I_F=10\text{A}, dI/dt=500\text{A}/\mu\text{s}$		20		ns
$Q_{\text{rr}}$	Body Diode Reverse Recovery Charge	$I_F=10\text{A}, dI/dt=500\text{A}/\mu\text{s}$		88		nC

A. The value of  $R_{\theta JA}$  is measured with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The Power dissipation  $P_{\text{DSM}}$  is based on  $R_{\theta JA}$  and the maximum allowed junction temperature of  $150^\circ\text{C}$ . The value in any given application depends on the user's specific board design, and the maximum temperature of  $175^\circ\text{C}$  may be used if the PCB allows it.

B. The power dissipation  $P_D$  is based on  $T_{J(\text{MAX})}=175^\circ\text{C}$ , using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Repetitive rating, pulse width limited by junction temperature  $T_{J(\text{MAX})}=175^\circ\text{C}$ . Ratings are based on low frequency and duty cycles to keep initial  $T_J=25^\circ\text{C}$ .

D. The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to case  $R_{\theta JC}$  and case to ambient.

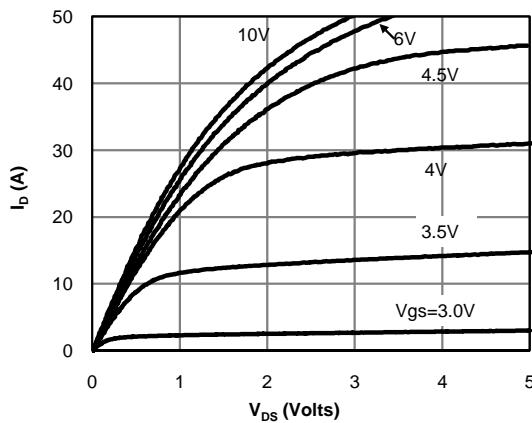
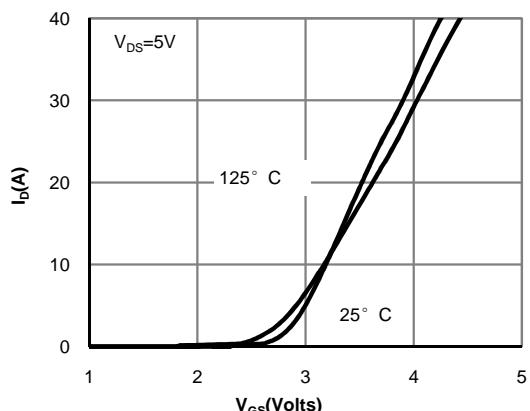
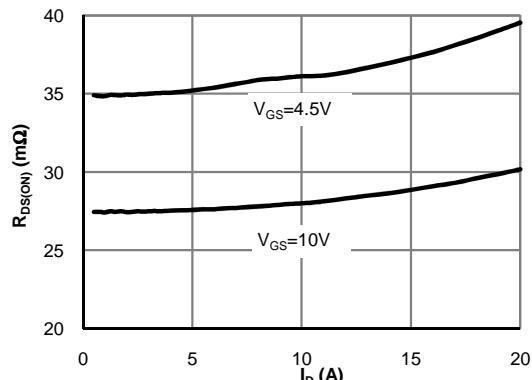
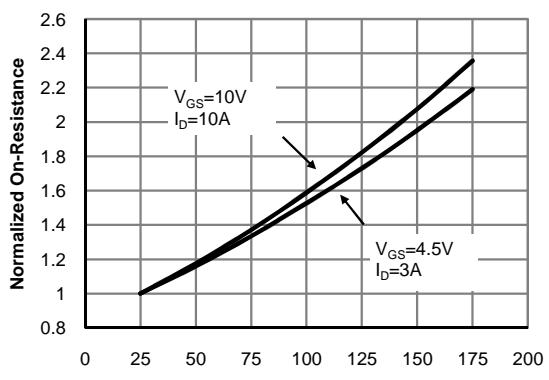
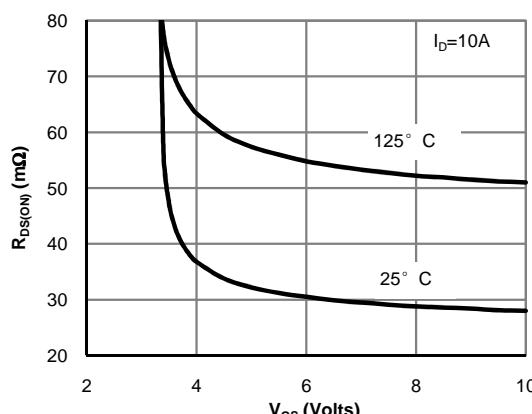
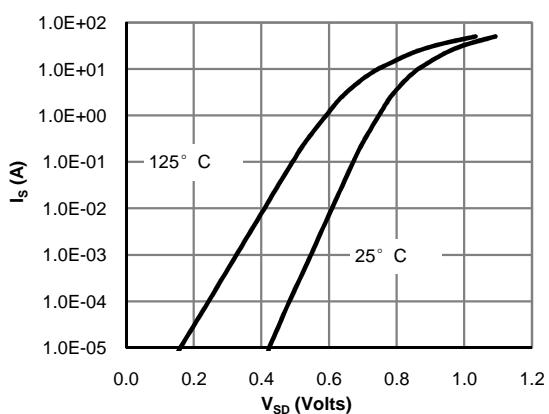
E. The static characteristics in Figures 1 to 6 are obtained using <300 $\mu\text{s}$  pulses, duty cycle 0.5% max.

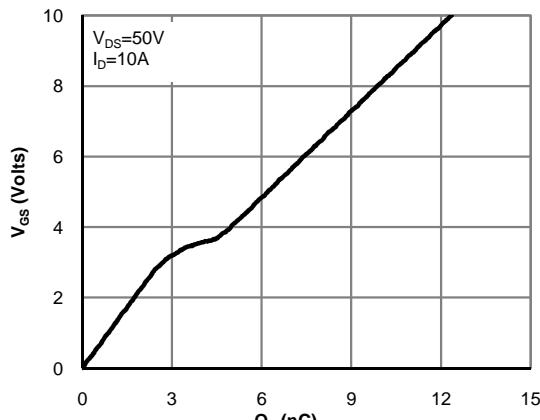
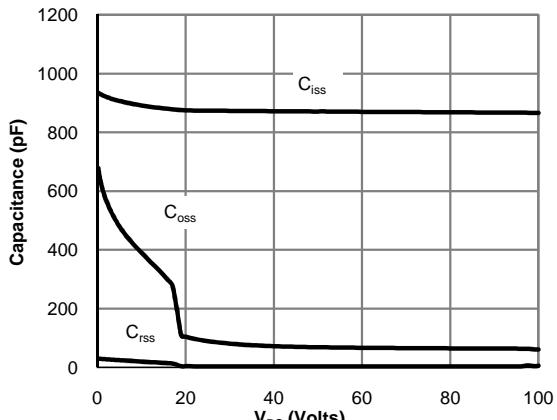
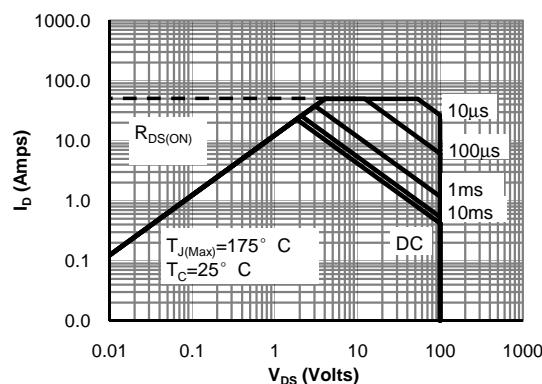
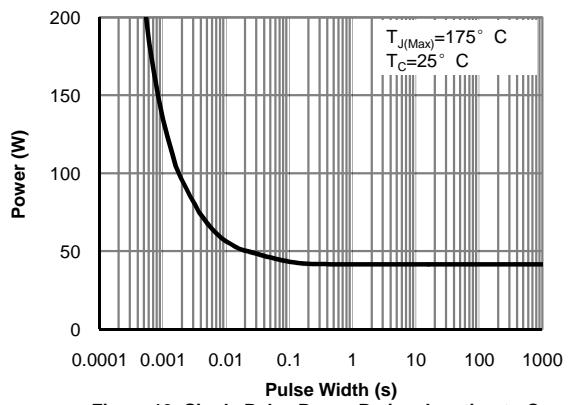
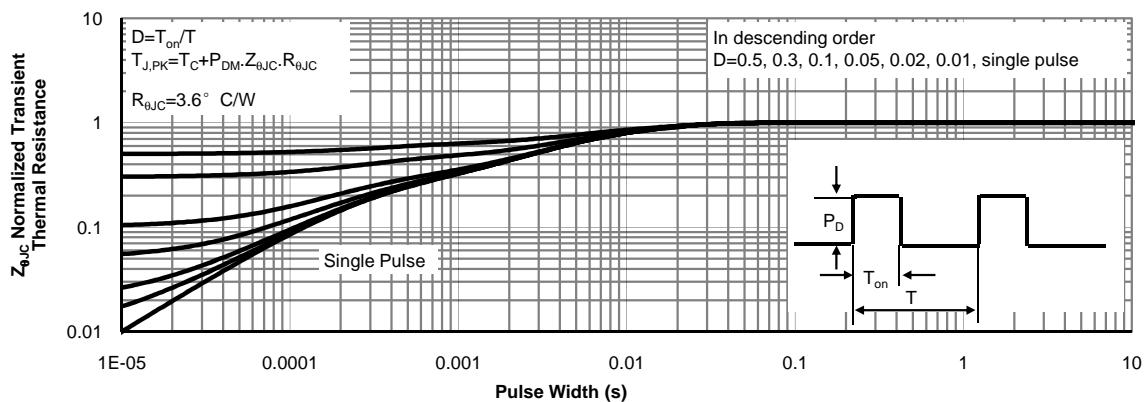
F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of  $T_{J(\text{MAX})}=175^\circ\text{C}$ . The SOA curve provides a single pulse rating.

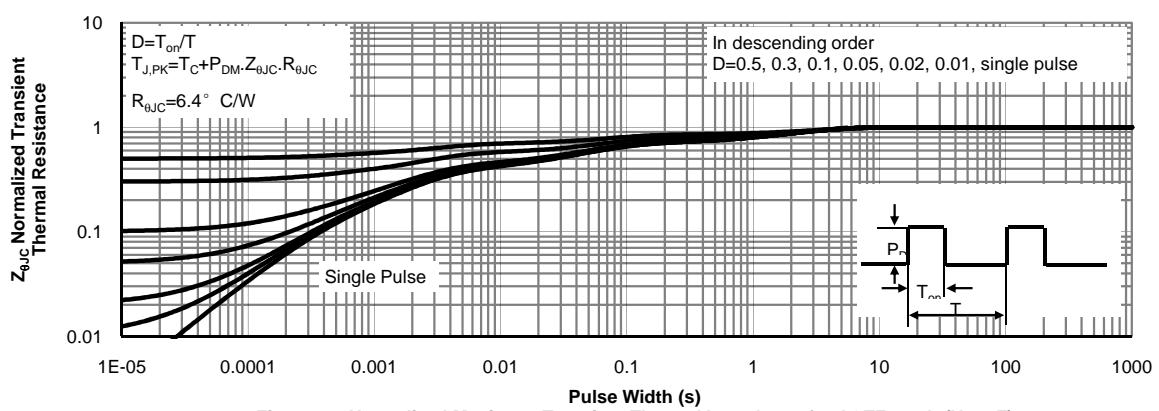
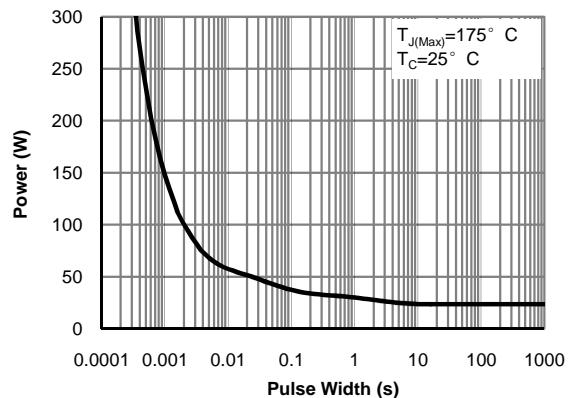
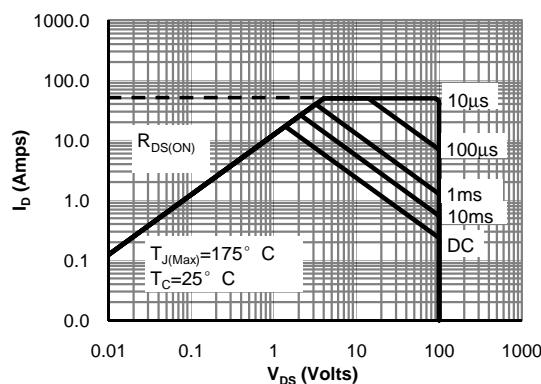
G. The maximum current limited by package.

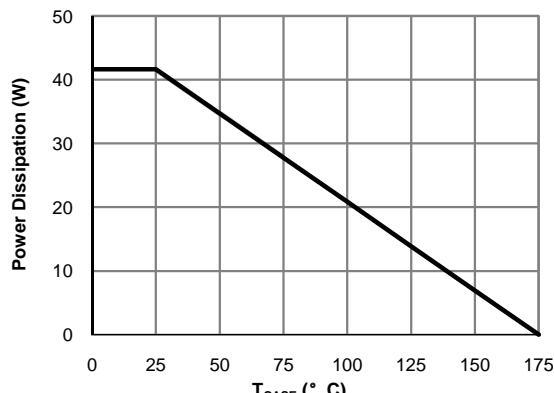
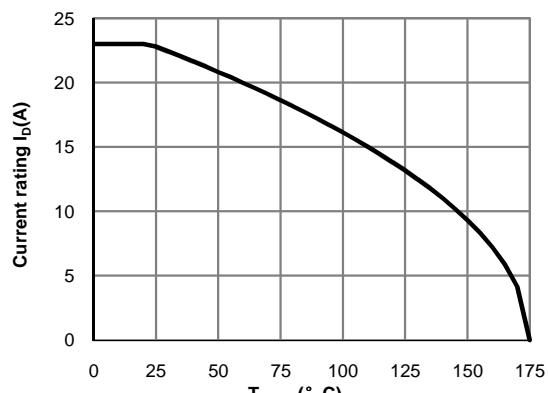
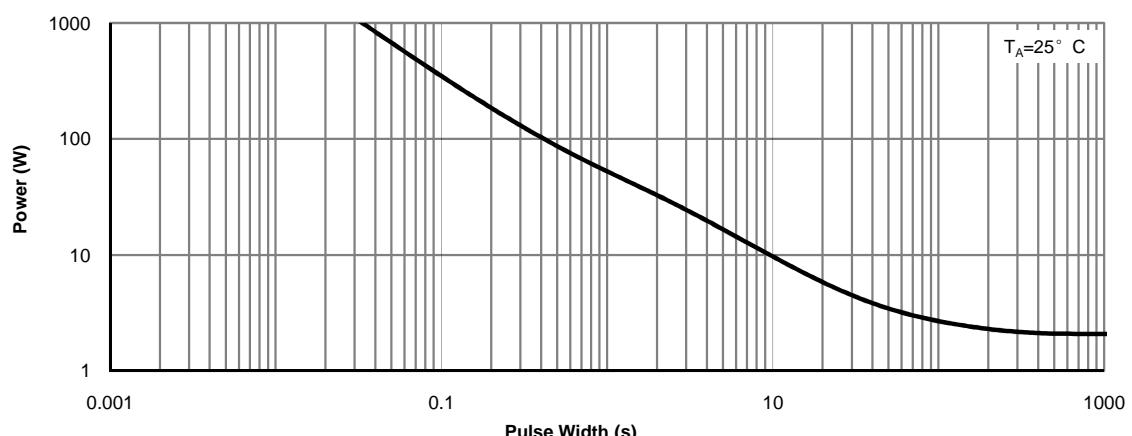
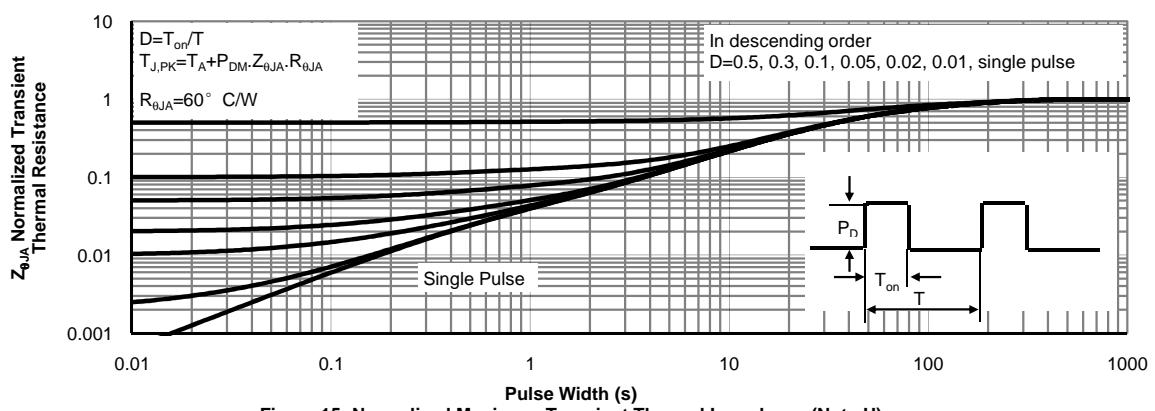
H. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ .

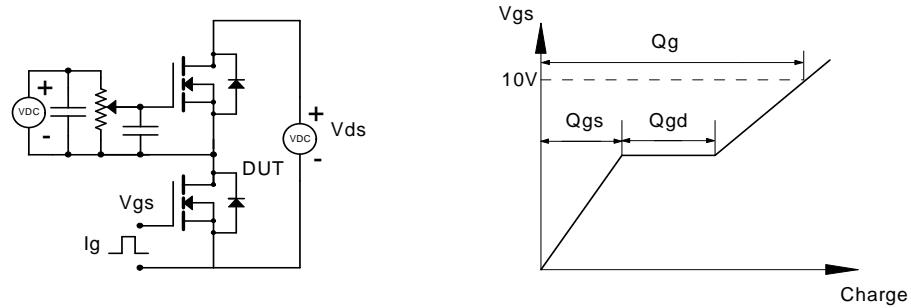
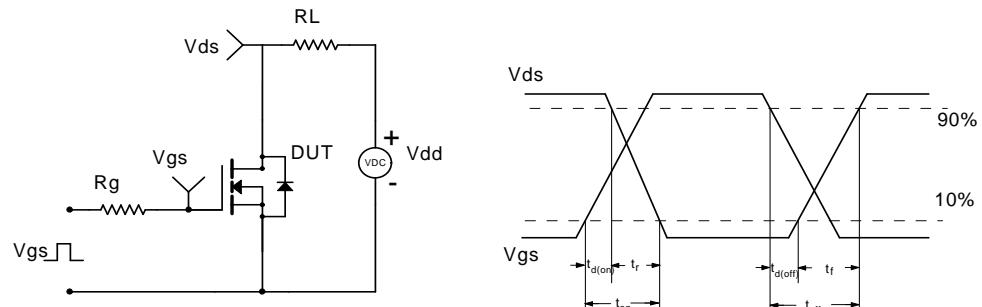
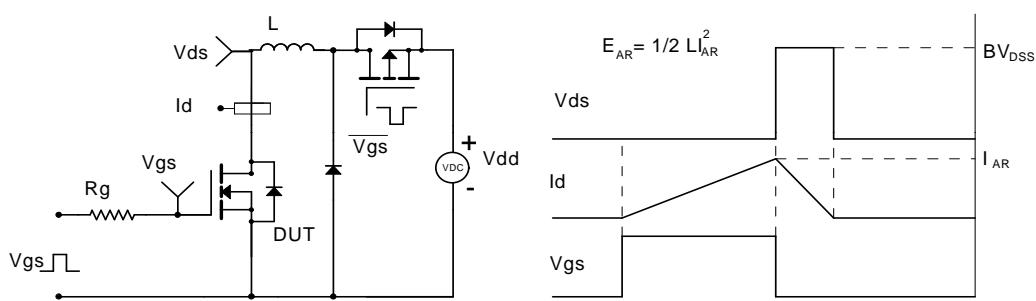
THIS PRODUCT HAS BEEN DESIGNED AND QUALIFIED FOR THE CONSUMER MARKET. APPLICATIONS OR USES AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS ARE NOT AUTHORIZED. AOS DOES NOT ASSUME ANY LIABILITY ARISING OUT OF SUCH APPLICATIONS OR USES OF ITS PRODUCTS. AOS RESERVES THE RIGHT TO IMPROVE PRODUCT DESIGN, FUNCTIONS AND RELIABILITY WITHOUT NOTICE.

**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

**Fig 1: On-Region Characteristics (Note E)**

**Figure 2: Transfer Characteristics (Note E)**

**Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)**

**Figure 4: On-Resistance vs. Junction Temperature (Note E)**

**Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)**

**Figure 6: Body-Diode Characteristics (Note E)**

**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

**Figure 7: Gate-Charge Characteristics**

**Figure 8: Capacitance Characteristics**

**Figure 9: Maximum Forward Biased Safe Operating Area for AOT2916L (Note F)**

**Figure 10: Single Pulse Power Rating Junction-to-Case for AOT2916L (Note F)**

**Figure 11: Normalized Maximum Transient Thermal Impedance for AOT2916L (Note F)**

**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**


**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

**Figure 12: Power De-rating (Note F)**

**Figure 13: Current De-rating (Note F)**

**Figure 14: Single Pulse Power Rating Junction-to-Ambient (Note H)**

**Figure 15: Normalized Maximum Transient Thermal Impedance (Note H)**

**Gate Charge Test Circuit & Waveform**

**Resistive Switching Test Circuit & Waveforms**

**Unclamped Inductive Switching (UIS) Test Circuit & Waveforms**

**Diode Recovery Test Circuit & Waveforms**
